

October 1987 Revised January 1999

## CD4014BC 8-Stage Static Shift Register

### **General Description**

The CD4014BC is an 8-stage parallel input/serial output shift register. A parallel/serial control input enables individual JAM inputs to each of 8 stages. Q outputs are available from the sixth, seventh and eighth stages. All outputs have equal source and sink current capabilities and conform to standard "B" series output drive.

When the parallel/serial control input is in the logical "0" state, data is serially shifted into the register synchronously with the positive transition of the clock. When the parallel/ serial control input is in the logical "1" state, data is jammed into each stage of the register synchronously with the positive transition of the clock.

All inputs are protected against static discharge with diodes to  $\rm V_{DD}$  and  $\rm V_{SS}.$ 

#### **Features**

- Wide supply voltage range: 3.0V to 15V
- High noise immunity: 0.45 V<sub>DD</sub> (typ.)
- Low power TTL compatibility: Fan out of 2 driving 74L or 1 driving 74LS
- 5V-10V-15V parametric ratings
- Symmetrical output characteristics
- Maximum input leakage:

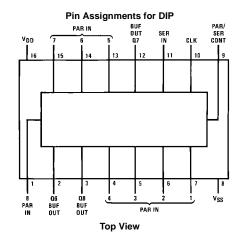
1  $\mu A$  at 15V over full temperature range

### **Ordering Code:**

Order Number	Package Number	Package Description
CD4014BCM	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
CD4014BCN	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "x" to the ordering code.

### **Connection Diagram**



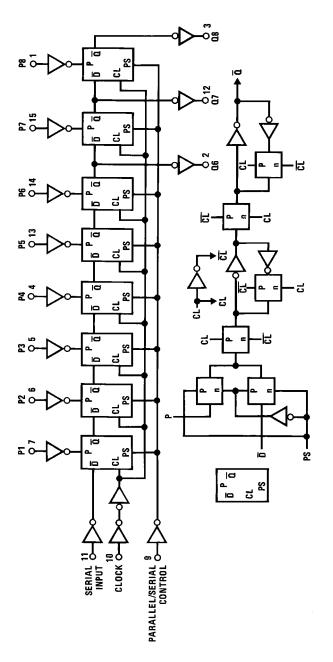
#### **Truth Table**

CL (Note 1)	Serial Input	Parallel/ Serial Control	PI 1	PI n	Q1 (Internal)	Q <sub>n</sub>
	Χ	1	0	0	0	0
~	X	1	1	0	1	0
~	X	1	0	1	0	1
~	Χ	1	1	1	1	1
~	0	0	Х	Х	0	$Q_{n-1}$
~	1	0	Х	Χ	1	$Q_{n-1}$
~	X	Χ	Х	Х	Q1	$Q_n$

X = Don't care case No Change

Note 1: Level change

# Logic Diagram



### Absolute Maximum Ratings(Note 2)

(Note 3)

 $\begin{tabular}{ll} Supply Voltage (V_{DD}) & -0.5V to +18V \\ Input Voltage (V_{IN}) & -0.5 to V_{DD} + 0.5V \\ Storage Temperature Range (T_S) & -65^{\circ}C to +150^{\circ}C \\ \end{tabular}$ 

Power Dissipation (P<sub>D</sub>)

Dual-In-Line 700 mW Small Outline 500 mW

Lead Temperature (T<sub>L</sub>)

(Soldering, 10 seconds) 260°C

## Recommended Operating Conditions (Note 3)

Note 2: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

Note 3:  $V_{SS} = 0V$  unless otherwise specified.

### DC Electrical Characteristics (Note 3)

Symbol	Parameter	Conditions		-40°C		+25°C			+85°C		Units
Symbol	Farameter			Min	Max	Min	Тур	Max	Min	Max	Ullits
I <sub>DD</sub>	Quiescent Device	$V_{DD} = 5V$ , $V_{IN} = V_{DD}$ or $V_{SS}$ $V_{DD} = 10V$ , $V_{IN} = V_{DD}$ or $V_{SS}$			20		0.1	20		150	μΑ
	Current				40		0.2	40		300	μΑ
		$V_{DD} = 15V, V_{IN} = V$	<sub>DD</sub> or V <sub>SS</sub>		80		0.3	80		600	μΑ
V <sub>OL</sub>	LOW Level	$V_{DD} = 5V$			0.05		0	0.05		0.05	V
	Output Voltage	$V_{DD} = 10V$	$ I_O  < 1  \mu A$		0.05		0	0.05		0.05	V
		$V_{DD} = 15V$			0.05		0	0.05		0.05	V
V <sub>OH</sub>	HIGH Level	$V_{DD} = 5V$		4.95		4.95	5		4.95		V
	Output Voltage	$V_{DD} = 10V$	$ I_O  < 1  \mu A$	9.95		9.95	10		9.95		V
		$V_{DD} = 15V$		14.95		14.95	15		14.95		V
$V_{IL}$	LOW Level	$V_{DD} = 5V, V_{O} = 0.5$	V or 4.5V		1.5		2	1.5		1.5	V
	Input Voltage	$V_{DD} = 10V, V_{O} = 1.$	0V or 9.0V		3.0		4	3.0		3.0	V
		$V_{DD} = 15V, V_{O} = 1.$	5V or 13.5V		4.0		6	4.0		4.0	V
V <sub>IH</sub>	$V_{IH}$ HIGH Level $V_{DD} = 5V$ , $V_{O} = 0.5V$ or 4.5V		3.5		3.5	3		3.5		V	
	Input Voltage	$\begin{split} &V_{DD} = 10V,  V_{O} = 1.0V \text{ or } 9.0V \\ &V_{DD} = 15V,  V_{O} = 1.5V \text{ or } 13.5V \\ &V_{DD} = 5V,  V_{O} = 0.5V \text{ or } 4.5V \\ &V_{DD} = 10V,  V_{O} = 1.0V \text{ or } 9.0V \\ &V_{DD} = 15V,  V_{O} = 1.5V \text{ or } 13.5V \end{split}$	7.0		7.0	6		7.0		V	
		$V_{DD} = 15V, V_{O} = 1.5V \text{ or } 13.5V$		11.0		11.0	9		11.0		V
I <sub>OL</sub>	LOW Level Output	$V_{DD} = 5V, V_{O} = 0.4V$		0.52		0.44	0.88		0.36		mA
	Current (Note 4)	$V_{DD} = 10V, V_{O} = 0.$	5V	1.3		1.1	2.2		0.9		mA
		$V_{DD} = 15V, V_{O} = 1.$	5V	3.6		3.0	8		2.4		mA
I <sub>OH</sub>	HIGH Level Output	$V_{DD} = 5V, V_{O} = 4.6$	V	-0.52		-0.44	-0.88		-0.36		mA
	Current (Note 4)	$V_{DD} = 10V, V_{O} = 9.$	5V	-1.3		-1.1	-2.2		-0.90		mA
		$V_{DD} = 15V, V_{O} = 13.5V$		-3.6		-3.0	-8		-2.4		mA
I <sub>IN</sub>	Input Current	V <sub>DD</sub> = 15V, V <sub>IN</sub> = 0V			-0.3		-10 <sup>-5</sup>	-0.3		-1.0	μΑ
		$V_{DD} = 15V, V_{IN} = 18$	5V		0.3		10 <sup>-5</sup>	0.3		1.0	μΑ

Note 4: I<sub>OL</sub> and I<sub>OH</sub> are tested one output at a time.

# AC Electrical Characteristics (Note 5) $T_A = 25^{\circ}C$ , input $t_r$ , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k $\Omega$

Symbol	Parameter	Conditions	Min	Тур	Max	Units
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay Time	$V_{DD} = 5V$		200	320	ns
		$V_{DD} = 10V$		80	160	ns
		$V_{DD} = 15V$		60	120	ns
t <sub>THL</sub> , t <sub>TLH</sub>	Transition Time	$V_{DD} = 5V$		100	200	ns
		$V_{DD} = 10V$		50	100	ns
		$V_{DD} = 15V$		40	80	ns
f <sub>CL</sub>	Maximum Clock	$V_{DD} = 5V$	2.8	4		MHz
	Input Frequency	$V_{DD} = 10V$	6	12		MHz
		$V_{DD} = 15V$	8	16		MHz
t <sub>W</sub>	Minimum Clock	$V_{DD} = 5V$		90	180	ns
	Pulse Width	$V_{DD} = 10V$		40	80	ns
		V <sub>DD</sub> = 15V		25	50	ns
t <sub>rCL</sub> , t <sub>fCL</sub>	Clock Rise and	$V_{DD} = 5V$			15	μs
	Fall Time (Note 6)	$V_{DD} = 10V$			15	μs
		$V_{DD} = 15V$			15	μs
t <sub>S</sub>	Minimum Set-Up Time	$V_{DD} = 5V$		60	120	ns
	(Note 7) Serial Input	$V_{DD} = 10V$		40	80	ns
	$t_H \ge 200 \text{ ns}$	$V_{DD} = 15V$		30	60	ns
	Parallel Inputs	$V_{DD} = 5V$		80	160	ns
	t <sub>H</sub> ≥ 200 ns	$V_{DD} = 10V$		40	80	ns
		$V_{DD} = 15V$		30	60	ns
	Parallel/Serial Control	$V_{DD} = 5V$		100	200	ns
	t <sub>H</sub> ≥ 200 ns	$V_{DD} = 10V$		50	100	ns
		$V_{DD} = 15V$		40	80	ns
t <sub>H</sub>	Minimum Hold Time	$V_{DD} = 5V$			0	ns
	Serial In, Parallel In, t <sub>S</sub> ≥ 400 ns	V <sub>DD</sub> = 10V			10	ns
	Parallel/Serial Control	$V_{DD} = 15V$			15	ns
CI	Average Input Capacitance	Any Input		5	7.5	pF
	(Note 8)					
C <sub>PD</sub>	Power Dissipation Capacitance			110		pF
	(Note 8)					

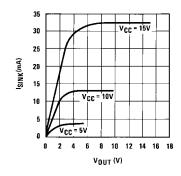
Note 5: AC Parameters are guaranteed by DC correlated testing.

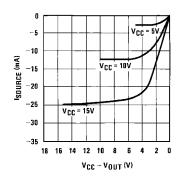
Note 6: If more than one unit is cascaded t<sub>rCL</sub> should be made less than or equal to the fixed propagation delay of the output of the driving stage for the esti-

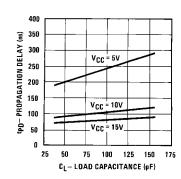
Note 7: Setup times are measured with reference to clock and a fixed hold time  $(t_{\text{H}})$  as specified.

Note 8: CPD determines the no load AC power consumption of any CMOS device. For complete explanation, see 74C family characteristics application note

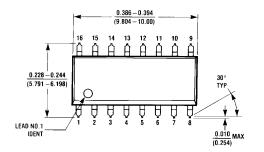
## **Typical Performance Characteristics**

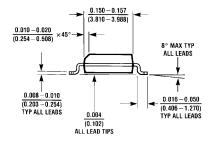


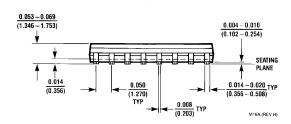




### Physical Dimensions inches (millimeters) unless otherwise noted

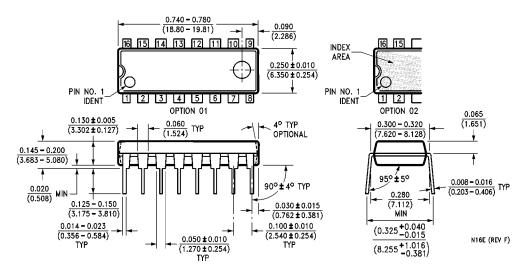






16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow Package Number M16A

### Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N16E

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